

INTERSIL

2N5117-2N5119 Dual Monolithic PNP Transistor

ABSOLUTE MAXIMUM RATINGS (25°C unless otherwise noted) (Note 1)

Dissipation at 25°C Case Temperature

Each side (Note 1)	0.4W
Both sides	0.75W

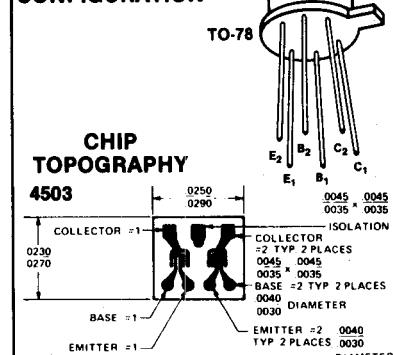
Derating Factor

Each side	2.3mW/°C
Both sides	4.3mW/°C

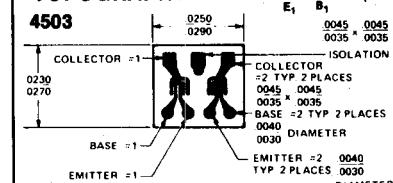
Voltage

Collector to Base	45V
Collector to Emitter	45V
Emitter to Base (Note 2)	7.0V
Collector to Collector	100V
Collector Current	10mA
Storage Temperature	-65 to +200°C
Lead Temperature for 10 Seconds	+300°C

PIN CONFIGURATION



CHIP TOPOGRAPHY



ORDERING INFORMATION

TO-78	WAFER	DICE
2N5117	2N5117/W	2N5117/D
2N5118	2N5118/W	2N5118/D
2N5119	2N5119/W	2N5119/D

ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

PARAMETER	2N5117		2N5119		UNIT	TEST CONDITIONS
	MIN	MAX	MIN	MAX		
h_{FE}	DC Current Gain	100	300	50		$I_C = 10 \mu A, V_{CE} = 5.0 V$
h_{FE}	DC Current Gain	100		50		$I_C = 500 \mu A, V_{CE} = 5.0 V$
h_{FE}	DC Current Gain (-55°C)	30		20		$I_C = 10 \mu A, V_{CE} = 5.0 V$
I_{CBO}	Collector Cutoff Current		0.1	0.1	nA	$I_E = 0, V_{CB} = 30 V$
I_{CBO}	Collector Cutoff Current (150°C)		0.1	0.1	μA	$I_E = 0, V_{CB} = 30 V$
I_{EBO}	Emitter Cutoff Current		0.1	0.1	nA	$I_C = 0, V_{EB} = 5.0 V$
I_{C1-C2}	Collector-Collector Leakage		5.0	5.0	pA	$V_{CC} = 100 V$
GBW	Current Gain Bandwidth Product	100		100	MHz	$I_C = 500 \mu A, V_{CE} = 10 V$
C_{ob}	Output Capacitance		0.8	0.8	pF	$I_E = 0, V_{CB} = 5.0 V$
C_{te}	Emitter Transition Capacitance		1.0	1.0	pF	$I_C = 0, V_{EB} = 0.5 V$
C_{C1-C2}	Collector-Collector Capacitance		0.8	0.8	pF	$V_{CC} = 0$
$V_{CEO(sust)}$	Collector-Emitter Sustaining Voltage	45		45	V	$I_C = 1.0 mA, I_B = 0$
NF	Narrow Band Noise Figure		4.0	4.0	dB	$I_C = 10 \mu A, V_{CE} = 5.0 V$ $f = 1 \text{ KHz}, R_G = 10 \text{ K}\Omega$ $BW = 200 \text{ Hz}$
$V_{(BR)CBO}$	Collector Base Breakdown Voltage	45		45	V	$I_C = 10 \mu A, I_E = 0$
$V_{(BR)EBO}$	Emitter Base Breakdown Voltage	7.0		7.0	V	$I_E = 10 \mu A, I_C = 0$

MATCHING CHARACTERISTICS (25°C unless otherwise noted)

PARAMETER	2N5117		2N5118		2N5119		UNIT	TEST CONDITIONS
	MIN	MAX	MIN	MAX	MIN	MAX		
h_{FE1}/h_{FE2}	DC Current Gain Ratio (Note 3)	0.9	1.0	0.85	1.0	0.8	1.0	
$V_{BE1}-V_{BE2}$	Base-Emitter Voltage Differential		3.0		5.0		5.0	mV
$I_{B1}-I_{B2}$	Base Current Differential		10.0		15		40	nA
$\Delta(V_{BE1}-V_{BE2})$	Base Voltage Differential Change with Temperature		3.0		5.0		10	$\mu V/\text{°C}$
$\Delta(I_{B1}-I_{B2})$	Base-Current Differential Change with Temperature		0.3		0.5		1.0	$nA/\text{°C}$

1. Maximum ratings are limiting values above which devices may be damaged. These ratings give a maximum junction temperature of 200°C.

2. The reverse base-to-emitter voltage must never exceed 7.0 volts and the reverse base-to-emitter current must never exceed 10 μA.

3. Lower of two h_{FE} readings is defined as h_{FE_1} .